

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 6,929,530 B1  
APPLICATION NO. : 09/616794  
DATED : August 16, 2005  
INVENTOR(S) : Jason B. Elledge

Page 1 of 2

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

<u>Should Read</u>		
Column 5, Line 4	“interferrometer”	--interferometer--
Column 7, Line 32	“system in defined”	--system is defined--
Column 8, Line 28	“substrate assembly the second view site”	--substrate assembly, the second view site--
Column 8, Line 43	“claim 1 wherein the”	--claim 1 wherein--
Column 9, Line 5	“planarizing medium—”	--planarizing medium--
Column 9, Line 13	“located at first area”	--located at a first area--
Column 9, Line 27	“substrate assembly the second view”	--substrate assembly, the second view--
Column 9, Line 32	“the-planarizing medium”	--the planarizing medium--
Column 10, Lines 22-23	“with the first elongated slot through the planarizing medium.”	--with the first elongated slot--
Column 10, Line 61	“substrate assembly the second view”	--substrate assembly, the second view--
Column 10, Line 66	“and a under surface,”	--and an under surface,--

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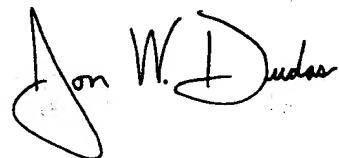
Page 2 of 2

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Should Read

Column 11, Line 44      "plurality of opening."      --plurality of openings.--

Signed and Sealed this  
Eighth Day of May, 2007



JON W. DUDAS  
*Director of the United States Patent and Trademark Office*